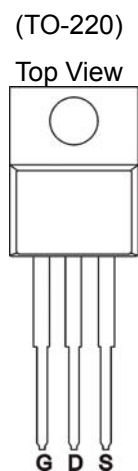


N- Channel 70-V (D-S) MOSFET

GENERAL DESCRIPTION

The HP80N70 is the N-Channel logic enhancement mode power field effect transistors are produced using high cell density, DMOS trench technology. This high density process is especially tailored to minimize on-state resistance.

PIN CONFIGURATION

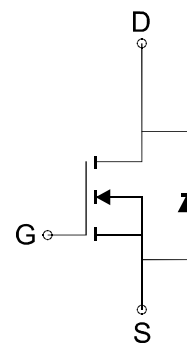


FEATURES

- $R_{DS(ON)} \leq 8.5m\Omega$ @ $V_{GS}=10V$
- Super high density cell design for extremely low $R_{DS(ON)}$
- Exceptional on-resistance and maximum DC current capability

APPLICATIONS

- Power Management
- DC/DC Converter
- Load Switch



N-Channel MOSFET

e Ordering Information: H P 80N75 (Pb-free)

H P80N75 (Green product-Halogen free)

Absolute Maximum Ratings ($T_c=25^\circ C$ Unless Otherwise Noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DSS}	70	V
Gate-Source Voltage	V_{GSS}	± 25	V
Continuous Drain Current*	I_D	$T_c=25^\circ C$	88
		$T_c=70^\circ C$	75
Pulsed Drain Current	I_{DM}	350	A
Maximum Power Dissipation	P_D	$T_c=25^\circ C$	180
		$T_c=70^\circ C$	120
Operating Junction and Storage Temperature Range	T_J	-55 to 175	$^\circ C$
Thermal Resistance-Junction to Case**	$R_{\theta JC}$	0.75	$^\circ C/W$

* Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 80A.

** The device mounted on $1in^2$ FR4 board with 2 oz copper.

N- Channel 70-V (D-S) MOSFET
Electrical Characteristics ($T_A=25^\circ\text{C}$ Unless Otherwise Specified)

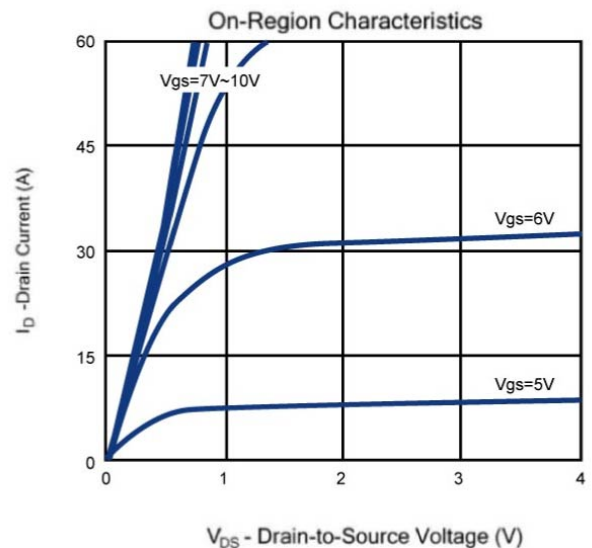
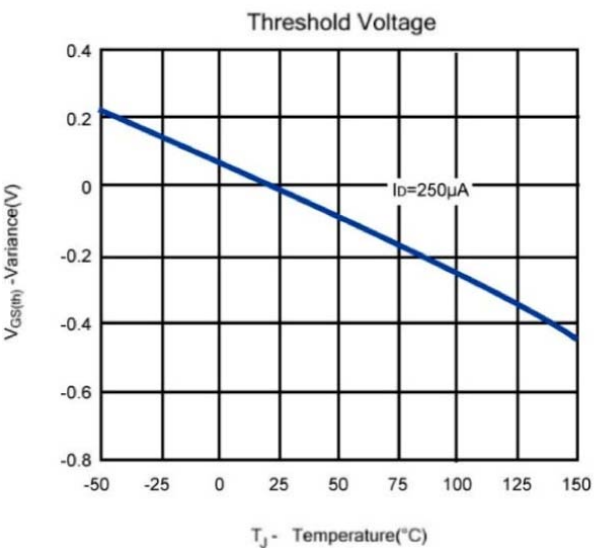
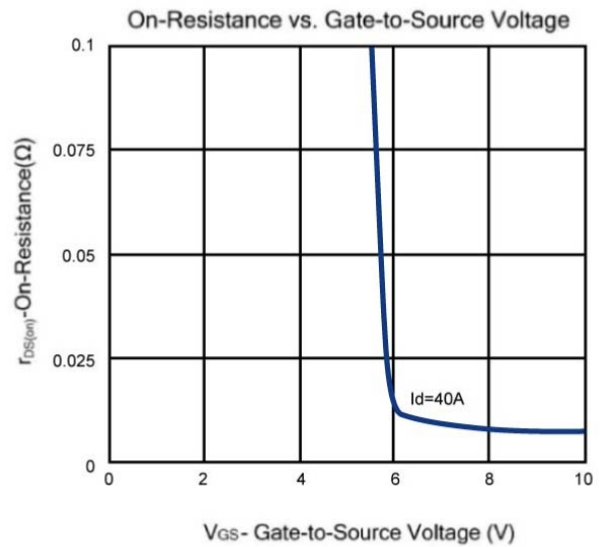
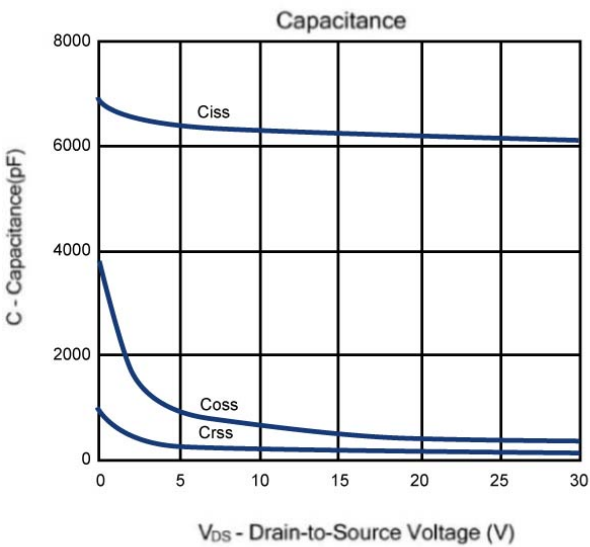
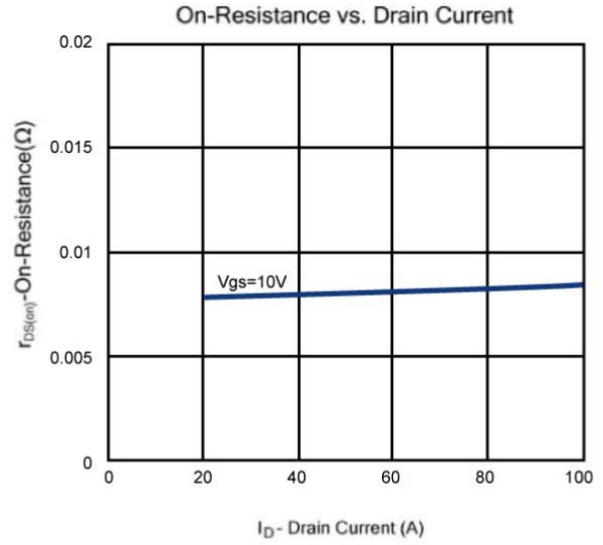
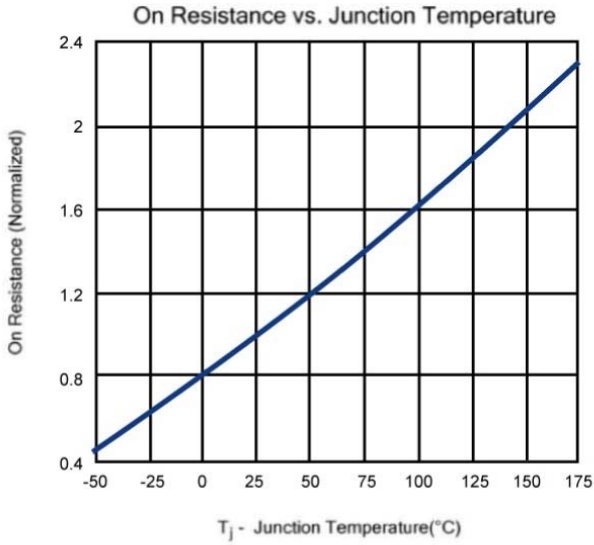
Symbol	Parameter	Limit	Min	Typ	Max	Unit
STATIC						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	70			V
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	2.0		4.0	V
I_{GSS}	Gate-Body Leakage	$V_{DS}=0V, V_{GS}=\pm 20V$			± 100	nA
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=70V, V_{GS}=0V$			1	μA
$R_{DS(on)}$	Drain-Source On-Resistance*	$V_{GS}=10V, I_D=40A$		7	8.5	$m\Omega$
V_{SD}	Diode Forward Voltage *	$I_S=40A, V_{GS}=0V$		0.9	1.3	V
DYNAMIC						
Q_g	Total Gate Charge	$V_{DD}=70V, V_{GS}=10V, I_D=80A$		134		nC
Q_g	Total Gate Charge	$V_{DD}=70V, V_{GS}=4.5V, I_D=80A$		27		
Q_{gs}	Gate-Source Charge			36		
Q_{gd}	Gate-Drain Charge			50		
R_g	Gate Resistance	$V_{DS}=0V, V_{GS}=0V, f=1MHz$		0.8		Ω
C_{iss}	Input Capacitance	$V_{DS}=20V, V_{GS}=0V, f=1MHz$		6200		pF
C_{oss}	Output Capacitance			437		
C_{rss}	Reverse Transfer Capacitance			144		
$t_{d(on)}$	Turn-On Delay Time	$V_{GS}=10V, R_L=15\Omega$ $V_{DD}=30V, R_G=10\Omega$		60		ns
t_r	Turn-On Rise Time			43		
$t_{d(off)}$	Turn-Off Delay Time			159		
t_f	Turn-Off Fall Time			47		

Notes: a. pulse test: pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$, Guaranteed by design, not subject to production testing.

b. Matsuki reserves the right to improve product design, functions and reliability without notice.

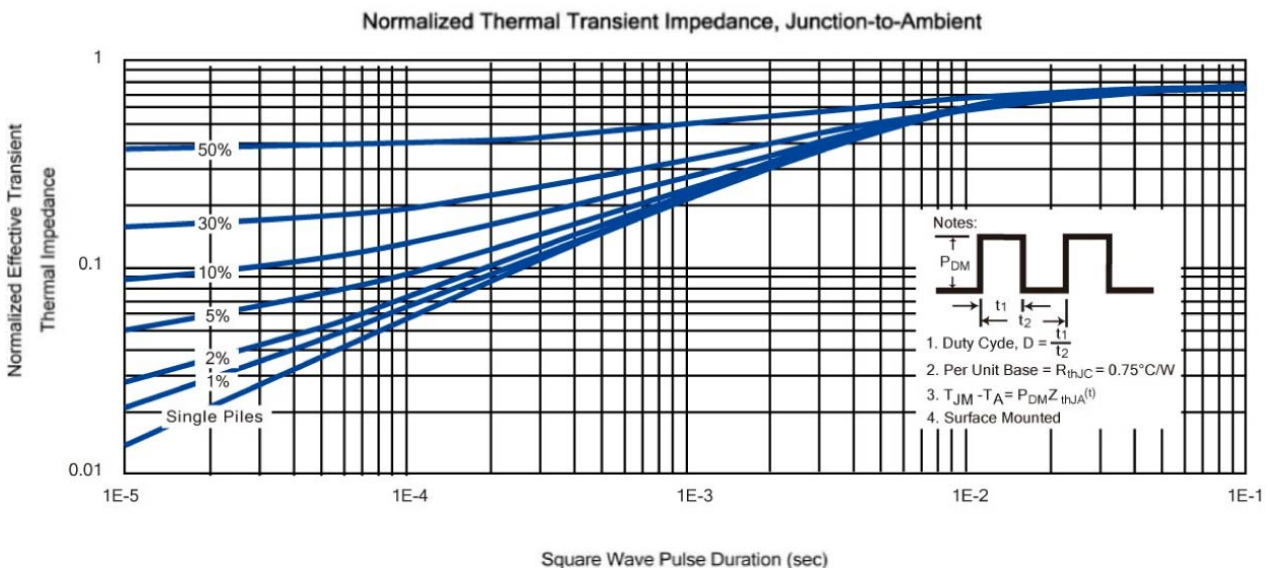
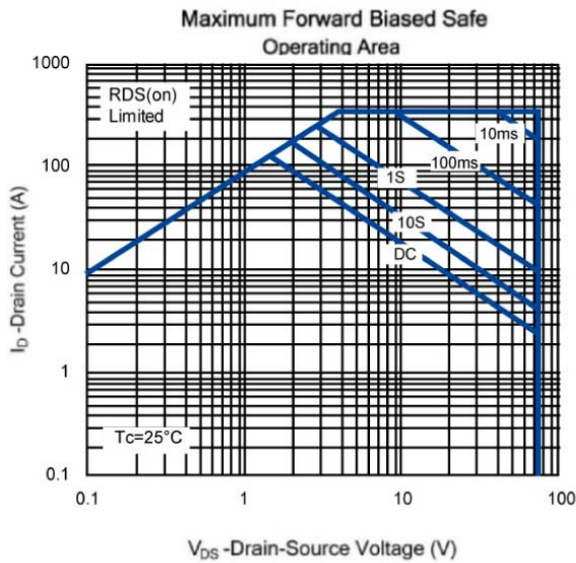
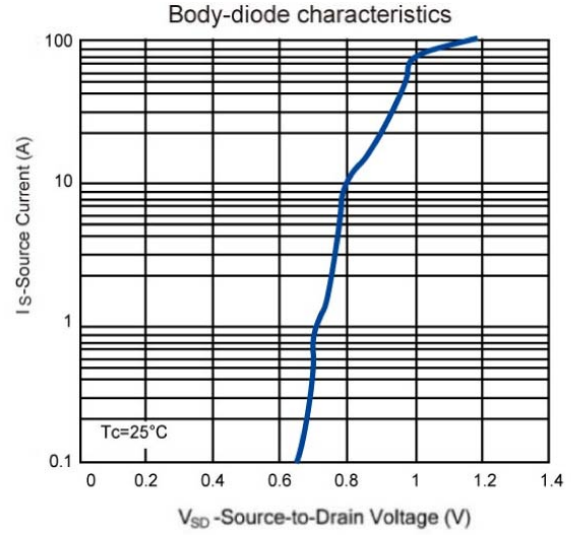
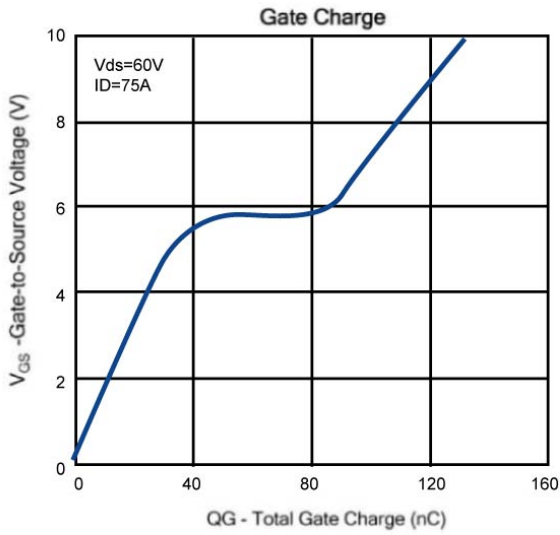
N- Channel 70-V (D-S) MOSFET

Typical Characteristics (T_J = 25°C Noted)



N- Channel 70-V (D-S) MOSFET

Typical Characteristics (T_J =25°C Noted)



TO-220

